

Electronic Supporting Information

Hybrid photocathode based on Ni molecular catalyst and Sb₂Se₃ for solar H₂ production

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1 Experimental details

1.1 Photocathode assembly $\text{Sb}_2\text{Se}_3/\text{CdS}/\text{TiO}_2\text{-meso}/\text{NiP}$

$\text{SnO}_2:\text{F}$ (FTO) coated glass substrates (TEC15, NSG group) were cleaned in ultrasonic baths of Hellmanex III detergent (2%), DI water and isopropyl alcohol in sequence, before drying with compressed nitrogen. A 70 nm Au layer (99.95%, Advent RM) was then thermally evaporated at a rate of $\sim 1 \text{ \AA s}^{-1}$. The Sb_2Se_3 absorber layer was deposited by close spaced sublimation (CSS) in a two-step process, with a small grain seed layer initially deposited under vacuum with a substrate temperature of 350°C to improve uniformity.^{1,2} This is followed by a higher temperature growth stage whereby the chamber is backfilled with 10 Torr N_2 and the substrate temperature is increased to 400°C to produce a $\sim 1.5 \text{ \mu m}$ thick film with a large grain size. RF magnetron sputtering was then used to deposit 20 nm CdS (60W, 5mTorr Ar, $T_{\text{sub}}=200^\circ\text{C}$) and 100 nm TiO_2 (150W, 3mTorr Ar, $T_{\text{sub}}=25^\circ\text{C}$) layers from 3” diameter compound targets.

1.2 TiO_2 mesoporous layer preparation

The method for preparation of TiO_2 mesoporous ($\text{TiO}_2\text{-meso}$) layer was initially optimized on FTO glass (TEC-15) cleaned in acetone, ethanol, DI water for 20 min each in an ultrasonic bath. Greatcell Solar® 18NR-T Titania Paste was slot coated using a glass pipette and Scotch® Magic™ Tape as template. To remove the organic binder present in the Titania paste, the films were UV cured using a 365 nm UV LED (2.9 W, 2.2 mm x 2.2 mm, LZ4-04UV00/ LED Engin) for 68 h was required, figure S5. The $\text{TiO}_2\text{-meso}$ layer was then sintered at 350°C under constant N_2 flow for 1 h with the final sample labelled as $\text{TiO}_2\text{-meso}(\text{UV})$. Profilometry measurements indicate that the UV cured film is *ca.* 4-6 \mu m thick. To compare the behaviour of the UV cured films to those prepared by a conventional thermal method, TiO_2 paste was deposited on FTO in the same manner and then annealed at 450°C under air during 1 h. Those samples were label as $\text{TiO}_2\text{-meso}(450^\circ\text{C}, \text{air})$. Once the TiO_2 mesoporous layer deposition made by UV curing was optimized, the same protocol was applied on the top of FTO/Au/ $\text{Sb}_2\text{Se}_3/\text{CdS}/\text{TiO}_2$ photoelectrodes. We labelled those samples as $\text{Sb}_2\text{Se}_3/\text{CdS}/\text{TiO}_2\text{-meso}$.

The **NiP** molecular catalyst was synthesized using previously described methods.³⁻⁶ **NiP** immobilization was achieved by soaking the samples in a 0.5 mM **NiP** solution prepared using dry methanol overnight (16 h) in the dark. Photoelectrodes were then rinsed thoroughly in dry methanol to remove the **NiP** excess not bound to the TiO_2 , followed by vacuum dried process at 60°C for 2 hr in the dark to remove methanol. The same experimental protocol was followed for the **NiP** immobilization in all the samples studied: planar device ($\text{Sb}_2\text{Se}_3/\text{CdS}/\text{TiO}_2$), the complete high surface area photoelectrode ($\text{Sb}_2\text{Se}_3/\text{CdS}/\text{TiO}_2\text{-meso}$), and the bare $\text{TiO}_2\text{-meso}$ (without the Sb_2Se_3 underneath) for the control experiments.

To determine the **NiP** loading, the photoelectrodes were soaked in 2 mL of 0.1 M NaOH for 1 h. The resultant **NiP** solution was studied using UV/Vis spectroscopy (Shimadzu 2300) and the concentration calculated by measuring the absorbance at 254 nm and through the use of a calibration curve made with known concentrations of **NiP** in 0.1 M NaOH.

1.3 Photoelectrodes characterization

Film thicknesses were measured *ex situ* using an Ambios XP-200 profilometer. Transmission and reflectance measurements were taken between 250-1500 nm using a Shimadzu SolidSpec-3700 UV-vis-NIR spectrophotometer in order to calculate the absorption coefficient, which was then used to estimate the band gap for CdS, Sb_2Se_3 and TiO_2 thin films according to the Tauc method.⁷

SEM and elemental analysis were taken on a Hitachi S4800 cold field emission gun (FEG) microscope detecting secondary electrons in the in-column detector. A working distance of 8 mm was used for all imaging. Voltage and gun current were set to 5 kV and 7 μ A respectively. Elemental analysis by SEM-EDX was carried out on the same samples using the same Hitachi S4800 microscope, with an Oxford Instruments AztecOne attachment with a 10 mm² silicon drift detector (SDD). A working distance of 15 mm was used for all elemental analysis. A voltage of 20 kV was selected based on the K α transition energies for Pt and Ni (Pt L α = 9.441 keV, Ni K α = 7.471 keV). Gun current was set to 15 μ A. The analysis was taken with the aperture completely removed to achieve maximum count rate whilst maintaining dead time <45%.

XPS data collection was performed at the EPSRC National Facility for XPS ('HarwellXPS'), operated by Cardiff University and UCL, under contract No. PR16195. XPS data was acquired using a Kratos Axis SUPRA using monochromated Al K α (1486.69 eV) X-rays at 12 mA emission and 12 kV HT (144W) and a spot size/analysis area of 700 x 300 μ m. The instrument was calibrated to gold metal Au 4f (83.95 eV) and dispersion adjusted give a BE of 932.6 eV for the Cu 2p_{3/2} line of metallic copper. Ag 3d_{5/2} line FWHM at 10 eV pass energy was 0.544 eV. Source resolution for monochromatic Al K α X-rays is ~0.3 eV. The instrumental resolution was determined to be 0.29 eV at 10 eV pass energy using the Fermi edge of the valence band for metallic silver. Resolution with charge compensation system on <1.33 eV FWHM on PTFE. High resolution spectra were obtained using a pass energy of 20 eV, step size of 0.1 eV and sweep time of 60s, resulting in a line width of 0.696 eV for Au 4f_{7/2}. Survey spectra were obtained using a pass energy of 160 eV. Charge neutralisation was achieved using an electron flood gun with filament current = 0.38 A, charge balance = 2 V, filament bias = 4.2 V. Successful neutralisation was adjudged by analysing the C 1s region wherein a sharp peak with no lower BE structure was obtained. Spectra have been charge corrected to the main line of the carbon 1s spectrum (adventitious carbon) set to 284.8 eV. All data was recorded at a base pressure of below 9 x 10⁻⁹ Torr and a room temperature of 294 K.

Raman analysis was carried out using a Raman microscope (Renishaw InVia) with a 50x objective (Leica). Before measurements, Raman band positions were calibrated *vs* the 520 cm⁻¹ silicon peak with a resolution of 1 cm⁻¹. A 532 nm green laser was used with 0.5% laser intensity for 60 s on Sb₂Se₃/CdS/TiO₂-*meso* and 5% laser intensity for 60 s for the sample without the TiO₂-*meso* layer (Sb₂Se₃/CdS/TiO₂). The same conditions were used pre, post N₂ annealing and post Controlled Potential Photoelectrolysis (CPP). To determine the effect of the N₂ annealing on the crystalline structure of the TiO₂ layer made RF magnetron sputtering 15% laser intensity was used for 60 s.

1.4 Photoelectrochemical measurements

A three-electrode cell was used for all the electrochemical measurements. Sb₂Se₃/CdS/TiO₂(-*meso*)/NiP was the working electrode, a Pt mesh was the counter electrode and Ag/AgCl (3 M NaCl) the reference electrode. The electrolyte was 0.1 M Na₂SO₄, pH 3 (adjusted with acetic acid) in Milli-Q water (18.2 M Ω ·cm) and a customised electrochemical cell was purged with N₂ for 25 min before each electrochemical test, figure S1.1. The pH 3 was chosen considering the highest catalytic activity of NiP towards H₂ production after being immobilised on TiO₂. It has been found that at lower (2) and higher (4) pH's the rate of hydrogen production decreased by > 50% and as well as the Faradic Efficiency.⁸

Electrochemical measurements were carried out using a PalmSens3 potentiostat. Linear sweep voltammetry (LSV) was conducted at 10 mV s⁻¹ from the open circuit potential in the cathodic direction. The electrochemical potentials were converted to the RHE according to Eq. (1)⁹

$$E \text{ (vs RHE)} = E \text{ (V vs Ag/AgCl)} + 0.059 * pH + 0.209 \quad (\text{Eq. 1})$$

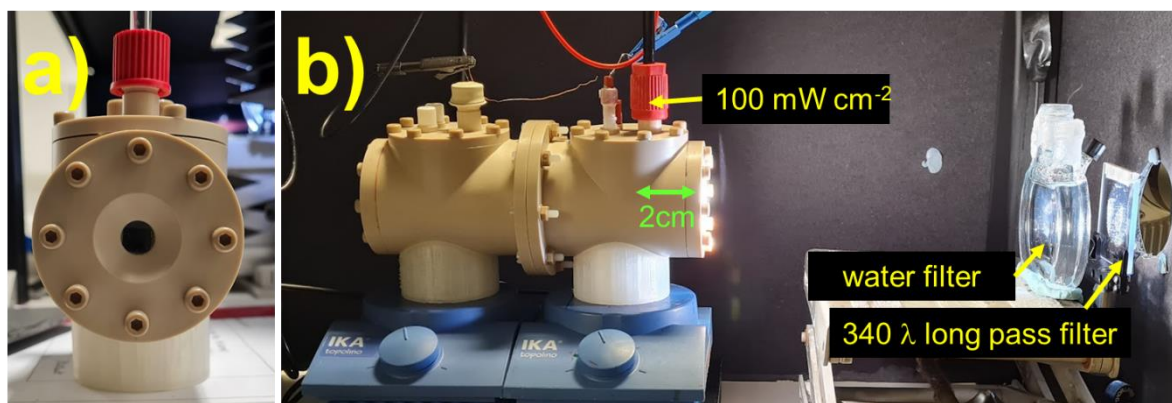


Figure S1.1 Customized photoelectrochemical cell used for the Controlled Potential Photoelectrolysis (CPP).

The light source was a Xe lamp providing an irradiation of 100 mW cm^{-2} (300 W Xe lamp, LOT Quantum Design) at the front of the electrochemical cell. Schott glass long pass filters were used to limit the output to $\lambda \geq 340 \text{ nm}$ and a water filter removed the infrared component, and a neutral density filter was used to decrease to drop the light intensity to 20 mW cm^{-2} . Photoelectrodes were front illuminated across a quartz window. Controlled potential photoelectrolysis (CPP) tests were carried out in a gas tight customised H cell at 0 V vs RHE with a Nafion membrane (N117) between the anode and cathode, for these experiments the electrochemical cell was purged for 30 min with N_2 and 1% CH_4 as an internal standard for gas chromatography. Gas compositions were determined using an Agilent 6890N instrument with helium N6 (BOC) as the carrier gas (5 mol min^{-1}), equipped with a 5 \AA molecular sieve column (ValcoPLOT, 30 m length, 0.53 mm ID) and a pulsed discharge detector (D-3-I-HP, Valco Vici).

Pt was photoelectrodeposited according to previous studies⁹ by applying a constant current of $-30 \text{ \mu A cm}^{-2}$ for 15 min under light irradiation of 100 mW cm^{-2} , $\lambda \geq 340 \text{ nm}$ and a water filter, in a solution containing $1 \text{ mM H}_2\text{PtCl}_6$ and $0.1 \text{ M Na}_2\text{SO}_4$.

IPCE measurements were carried out using 100 W tungsten lamp as a light source coupled with a monochromator (OBB Corp., typically set to 4 nm resolution). The light intensity was measured with a Si-photodiode detector (S120VC) and the IPCE was calculated using

$$IPCE (\%) = \frac{1240 * J}{\lambda * P} \quad \text{Eq (2)}$$

Where J is the photocurrent density (mA cm^{-2}) and P is the light power density (mW cm^{-2}) at each wavelength (λ). The IPCE spectra was collected at 0 V vs NHE .

2. Supporting figures

2.1. Band Gap (E_g) of the different semiconductors in the device

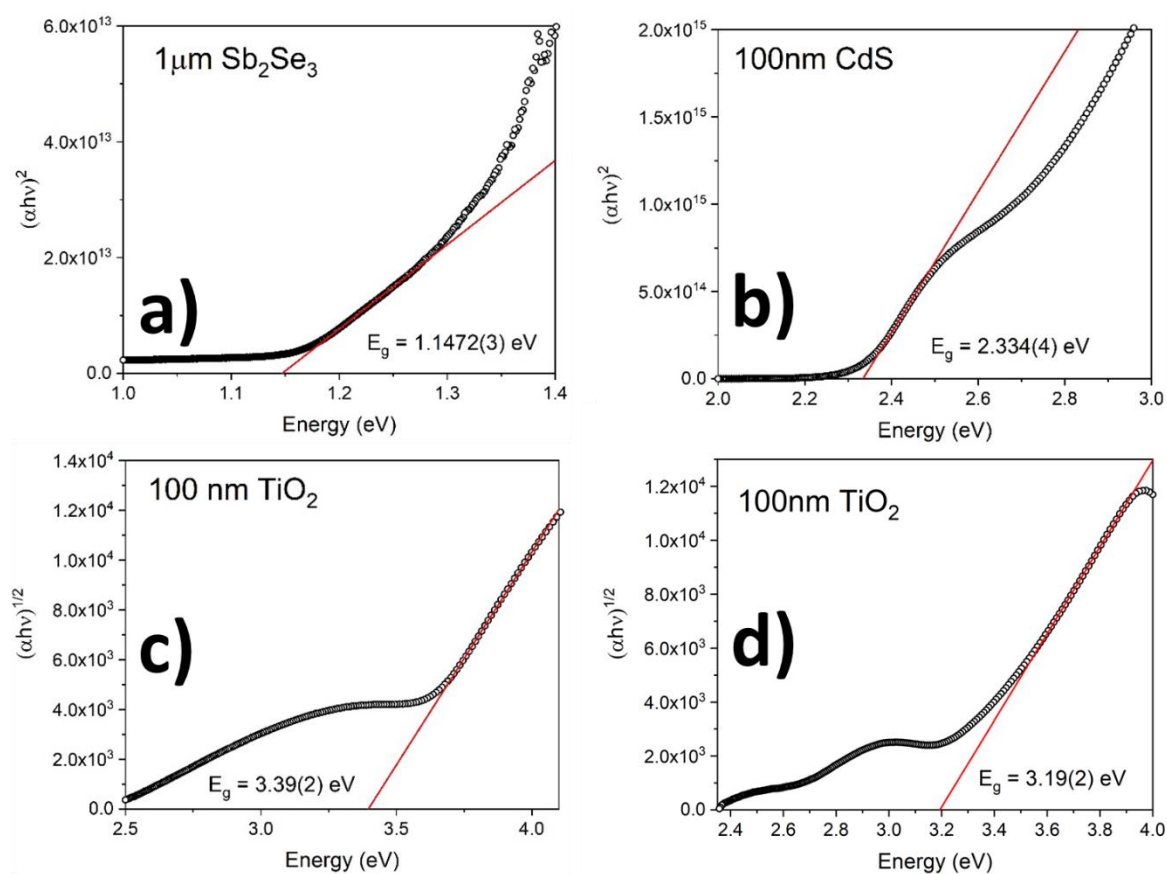


Figure S2.1. Tauc plots of (a) Sb_2Se_3 , (b) CdS , (c) TiO_2 fresh-made by RF magnetron sputtering, and (d) TiO_2 after N_2 annealing at 350°C

2.2. Raman analysis pre/post heat treatment

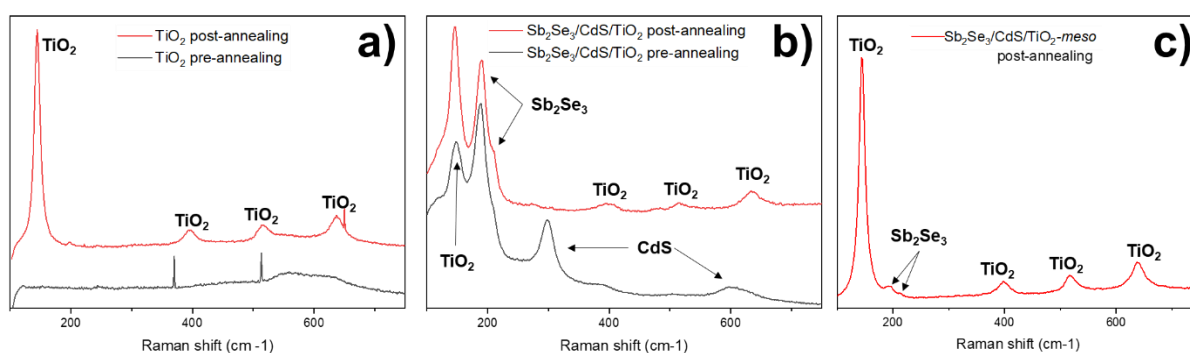


Figure S2.2. Raman spectra pre (black trace) and post (red trace) N_2 annealing at 350°C of (a) sputtered TiO_2 on FTO. Following annealing of the sputtered TiO_2 , Raman modes assignable to anatase TiO_2 were found. (b) $\text{Sb}_2\text{Se}_3/\text{CdS}/\text{TiO}_2$, and (c) $\text{Sb}_2\text{Se}_3/\text{CdS}/\text{TiO}_2\text{-meso}$.

2.3. SEM images before electrolysis

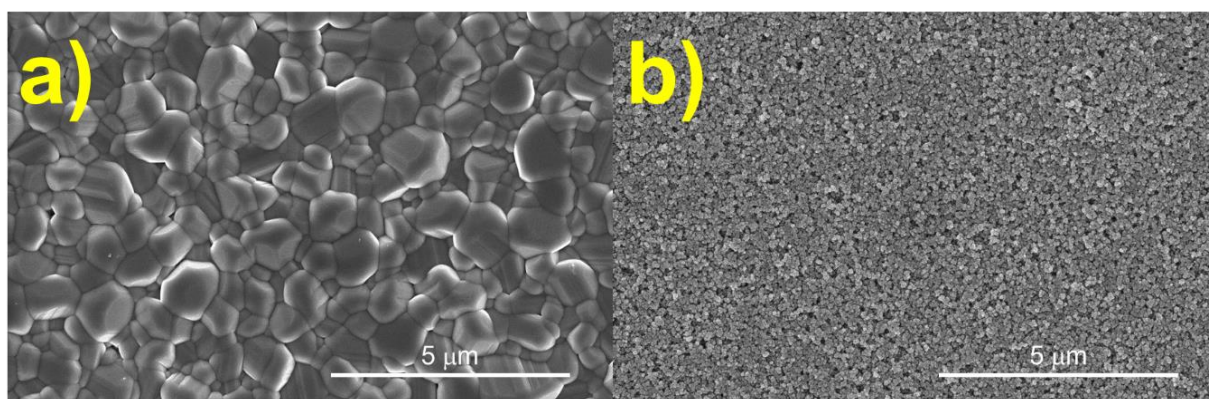


Figure S2.3 Top view SEM images of (a) $\text{Sb}_2\text{Se}_3/\text{CdS}/\text{TiO}_2$ and (b) $\text{Sb}_2\text{Se}_3/\text{CdS}/\text{TiO}_2\text{-meso}$.

2.4. LSV with no catalyst

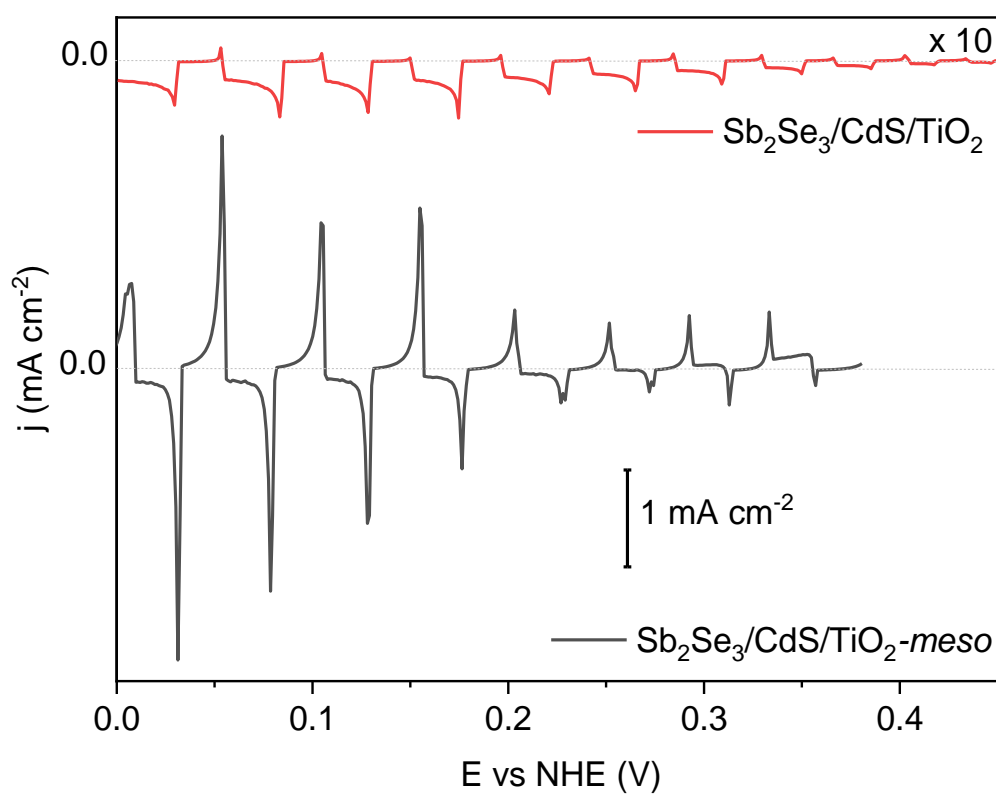


Figure S2.4: Light chopped LSV of $\text{Sb}_2\text{Se}_3/\text{CdS}/\text{TiO}_2\text{-meso}$ without catalyst in 0.1 M Na_2SO_4 pH 3 at 100 mW cm^{-2} and $\lambda > 340 \text{ nm}$.

2.5. Raman spectra of UV cured TiO_2 -*meso* films

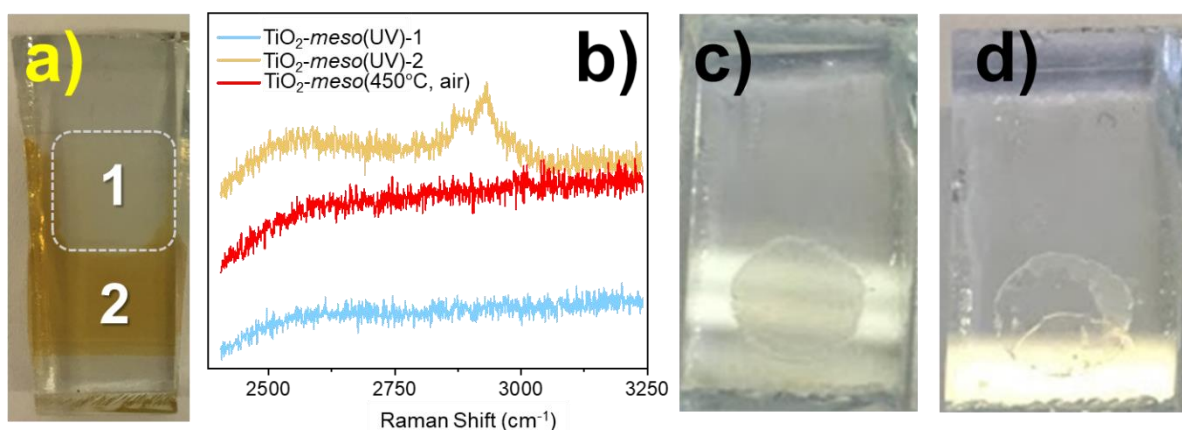


Figure S2.5 (a) TiO_2 -*meso*(UV) electrode. Region 1 has been UV-cured for 68 hrs and the α -terpinol is visibly removed. Region 2 has not been UV cured. (b) Raman spectra of region 1 (blue trace) and 2 (yellow trace) from panel (a), showing the absence of $\nu(\text{C-H})$ modes of α -terpinol¹⁰ at 2870 and 2910 cm^{-1} following curing. A Raman spectra of TiO_2 -*meso*(450°C, air shown as red trace) is also included as a control. TiO_2 -*meso*(UV) (c) before and (d) after being immersed in 0.1 M Na_2SO_4 pH 3. It is notable that in image (d) TiO_2 -*meso* layer delaminated following immersion in the electrolyte.

2.6. N₂ annealing of TiO₂-*meso*(UV)

To address the poor electrochemical properties and the low stabilities of the TiO₂-*meso*(UV) films in the electrolyte, samples were annealed under N₂ at 350 °C for 60 min to increase TiO₂ particle interconnectivity and to aid substrate adhesion. Figure S2.6 compares the electrochemical response by cyclic voltammetry (a) and Electrochemical Impedance Spectroscopy (EIS, b) of TiO₂-*meso*(UV) and the control sample prepared by typical thermal annealing TiO₂-*meso*(450 °C, air). Note that these electrochemical studies were carried out only with the mesoporous TiO₂ layer on FTO (without the underlying Sb₂Se₃/CdS/TiO₂-*sputtered* structure), for direct analysis of the annealing effect on the TiO₂-*meso*.

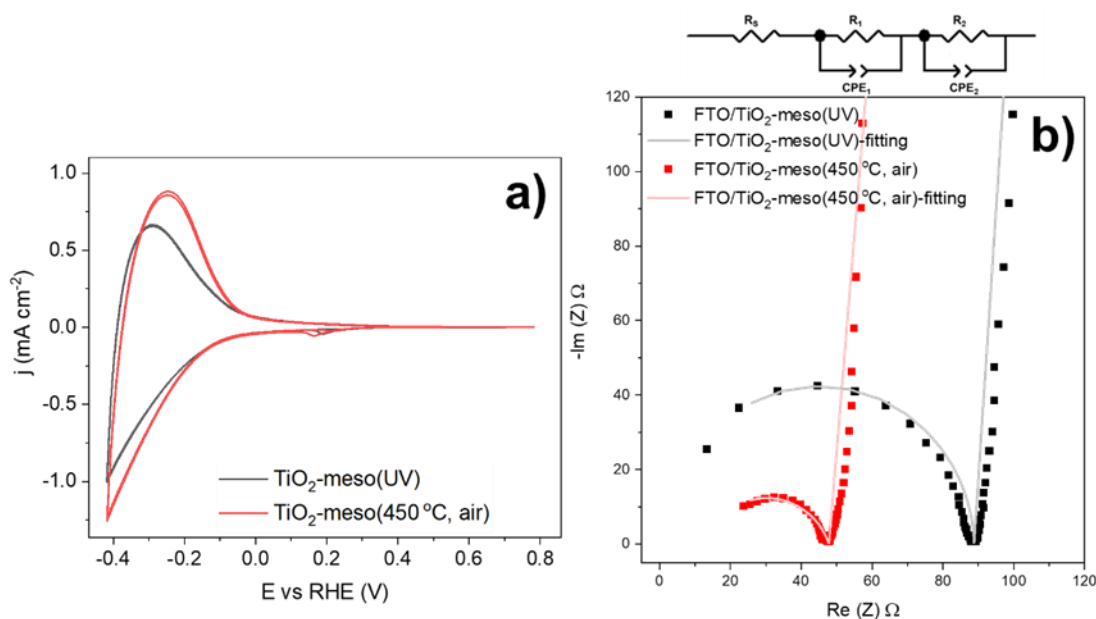


Figure S2.6 Comparison of the TiO₂-*meso* electrochemical properties made by UV curing followed by N₂ annealing at 350 °C (black trace) and the control sample annealed at 450 °C in air (red trace). (a) Cyclic voltammetry at 100 mV s⁻¹. (b) EIS spectra at 0 V vs RHE, with dots representing the experimental data and the fitted continuous line obtained using the equivalent circuit shown. Electrolyte: 0.1M Na₂SO₄ pH 3.

The N₂ annealing indeed aided the TiO₂ particle adhesion. However, the EIS analysis indicated the resistance of the TiO₂-*meso* film was higher for film made by UV curing than by the traditional air annealing process, being 87.2 and 35 Ω respectively.

Following annealing, NiP was immobilised on the TiO₂-*meso*(UV) and a control TiO₂-*meso*(450 °C, air) sample. Figure S2.7a shows the cyclic voltammetry at 100 mV s⁻¹ before and after the NiP immobilization on TiO₂-*meso*(UV) in 0.1M Na₂SO₄ pH 3, the bare TiO₂-*meso*(UV) displays the “trumpet shape” typically associated to the filling and emptying of the conduction band from the TiO₂. After the NiP immobilization, the oxidation current significantly diminishes indicating electron consumption by the molecular catalyst to produce H₂.⁸ Figure S2.7b compares the chronoamperometry test using a TiO₂ mesoporous sample made by UV curing (TiO₂-*meso*(UV)/NiP) vs the common annealing process (TiO₂-*meso*(450 °C, air)/NiP) after the catalyst immobilization at -0.25 V vs RHE in 0.1 M Na₂SO₄ pH 3. The electrochemical behaviour of both samples is similar with slightly lower current for the sample made by UV curing, presumably due to the higher film resistance, considering the similar catalyst loading (table S1).

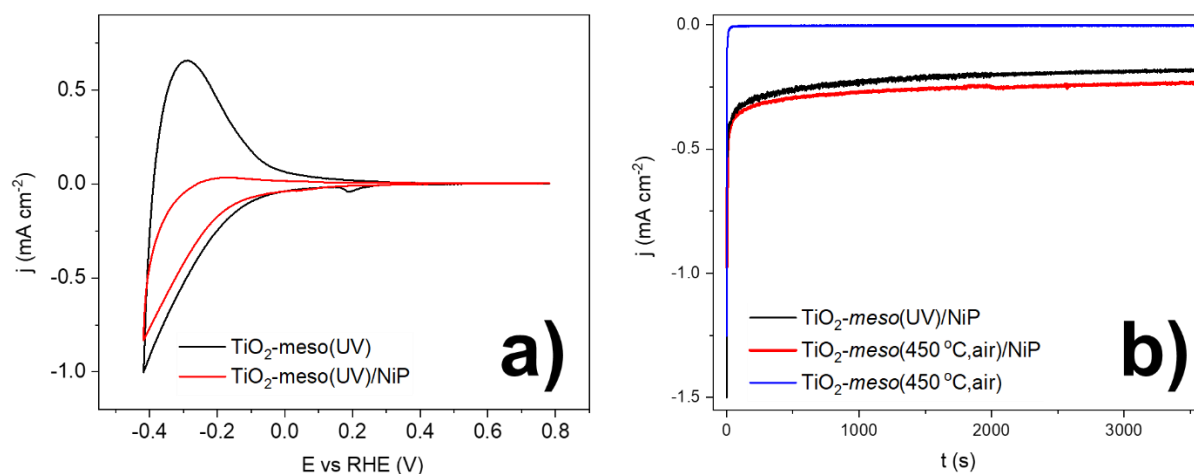


Figure S2.7. (a) Cyclic voltammetry before (black trace) and after the NiP immobilization (red trace) on TiO₂-meso(UV) in 0.1M Na₂SO₄ pH 3 at 100 mV s⁻¹. (b) Chronoamperometry test at -0.25 V vs RHE of TiO₂-meso/NiP with the TiO₂-meso layer made by air annealing (TiO₂-meso(450 °C, air)/NiP), and by 68h UV curing followed by N₂ annealing at 350 °C (TiO₂-meso(UV)/NiP) in 0.1 M Na₂SO₄ pH 3. The control sample with no catalyst, made by the typical thermal annealing TiO₂-meso(450 °C, air), showed low currents ~-4 μA cm⁻².

It is worthy to notice that N₂ annealing without the prior UV curing does not produce films with suitable properties to be used as TiO₂ mesoporous scaffold. Figure S2.8 shows pictures of TiO₂-meso after N₂ annealing without prior UV curing at different temperatures: 234, 350 and 450 °C in panel (a), and panel (b) presents the UV-Vis spectra of those samples. Not only the colour was not suitable for the TiO₂ scaffold, also the mechanical properties were compromised, and the TiO₂ was delaminated after the immersion in an electrolyte.

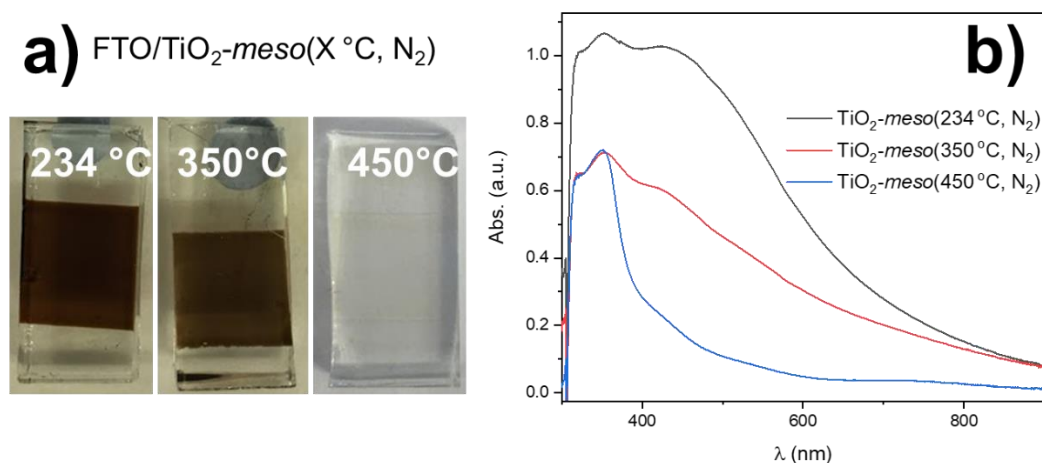


Figure S2.8. (a) Pictures of TiO₂-meso after N₂ annealing at different temperatures 234, 350 and 450 °C for 1 h, (b) UV-Vis spectra of those samples, without prior UV curing.

From figure S2.8, it is evident that only after increasing the temperature upon 450 °C during the N₂ annealing, the transparency and mechanical properties of the film were improved. However, at this temperature the stability of the light absorber is compromised. Previously, it has been reported that the interdiffusion at the Sb₂Se₃/CdS interface hinders light absorption in solar cells following a thermal annealing.^{11,12} To assess the stability of this interface after the annealing at 350 °C under N₂, a control photoelectrochemical experiment was carried out using Pt as benchmark catalyst for H₂ (see section 1.4 of SI for synthetic details). Figure S2.9 shows the light chopped LSV of Sb₂Se₃/CdS/TiO₂/Pt with and without the N₂ annealing at 350 °C at 10 mV s⁻¹ in 0.1 M H₂SO₄ with light intensity of 100 mW cm⁻²

and $\lambda > 340$ nm. It was found that the photocurrent increased followed the annealing demonstrating that the Sb_2Se_3 absorber can tolerate these conditions. Furthermore, the increase in photocurrent is likely associated to the improvement in crystallinity of the RF magnetron sputtered TiO_2 layer after the N_2 annealing as shown before in figure S2.2.^{13,14}

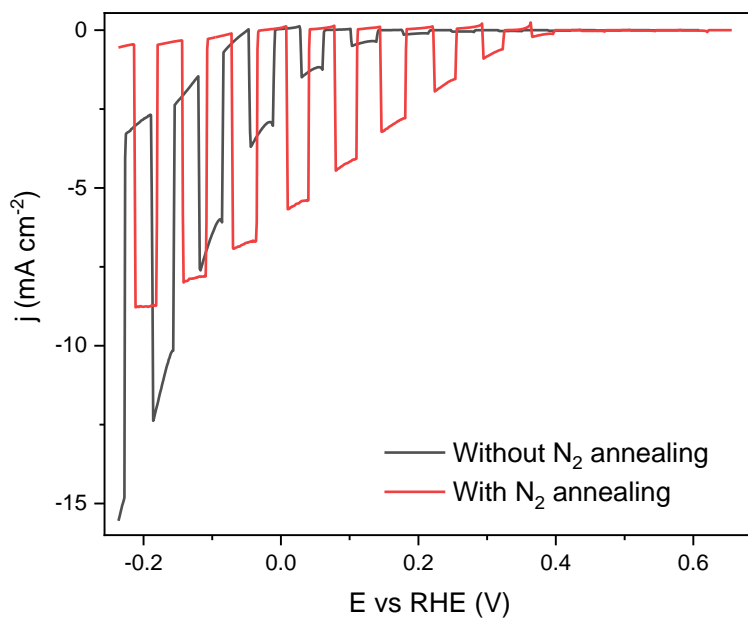


Figure S2.9: Light chopped LSV of $\text{Sb}_2\text{Se}_3/\text{CdS}/\text{TiO}_2/\text{Pt}$ with and without N_2 annealing at 350 °C for 1 h in 0.1 M H_2SO_4 at 100 mW cm^{-2} and $\lambda > 340$ nm.

S10. Cross-sectional SEM image of $\text{Sb}_2\text{Se}_3/\text{CdS}/\text{TiO}_2\text{-meso}$ and EDX maps

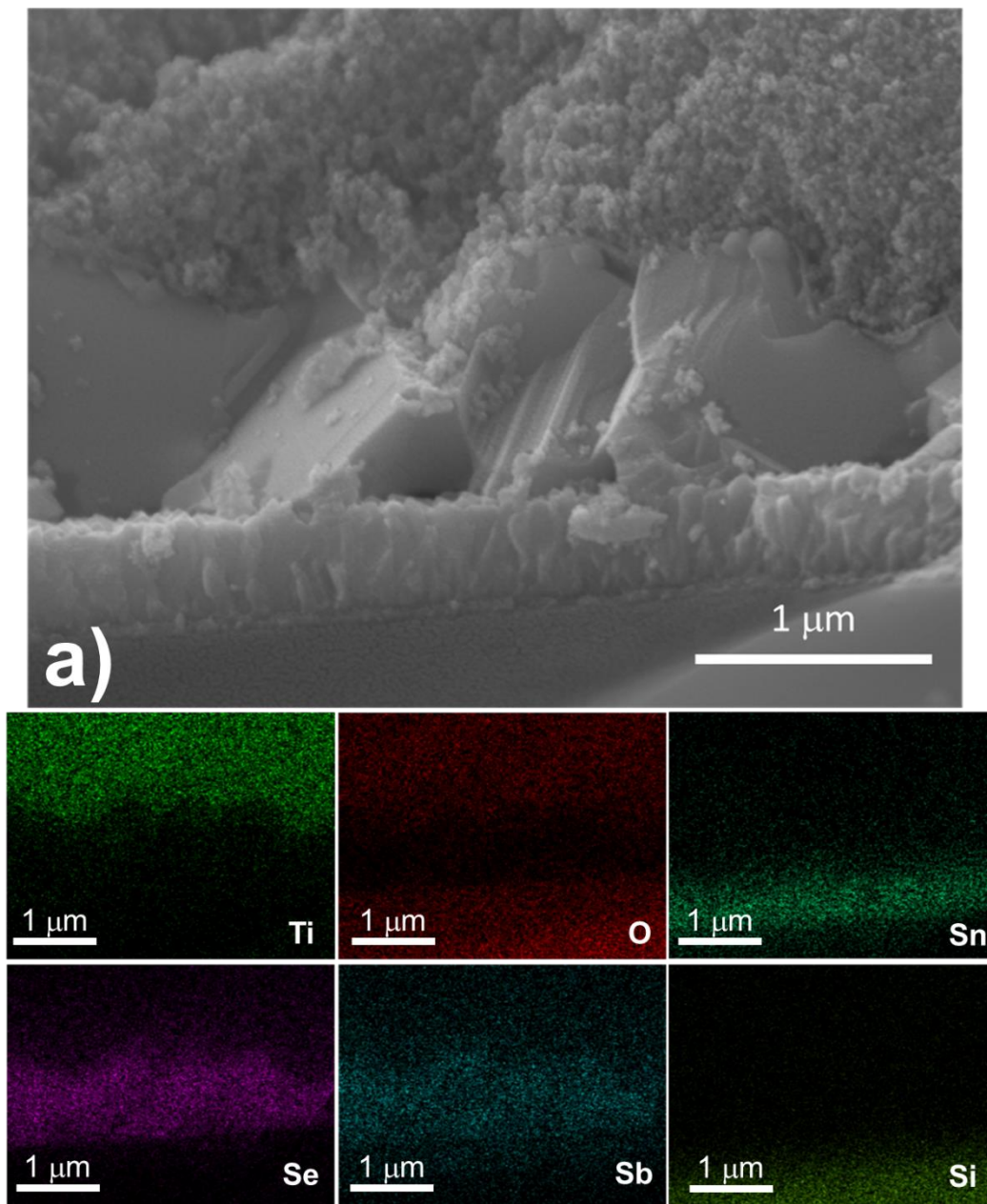


Figure S2.10. (a) Cross-sectional SEM image of $\text{Sb}_2\text{Se}_3/\text{CdS}/\text{TiO}_2\text{-meso}$ and EDX maps of Ti, O, Sn, Se, Sb, Si. Note that, since the thickness of Au and CdS layers are 70 nm and 20 nm, it was not possible to detect them.

2.11. Top view EDX analysis of NiP on $\text{Sb}_2\text{Se}_3/\text{CdS}/\text{TiO}_2$ -meso

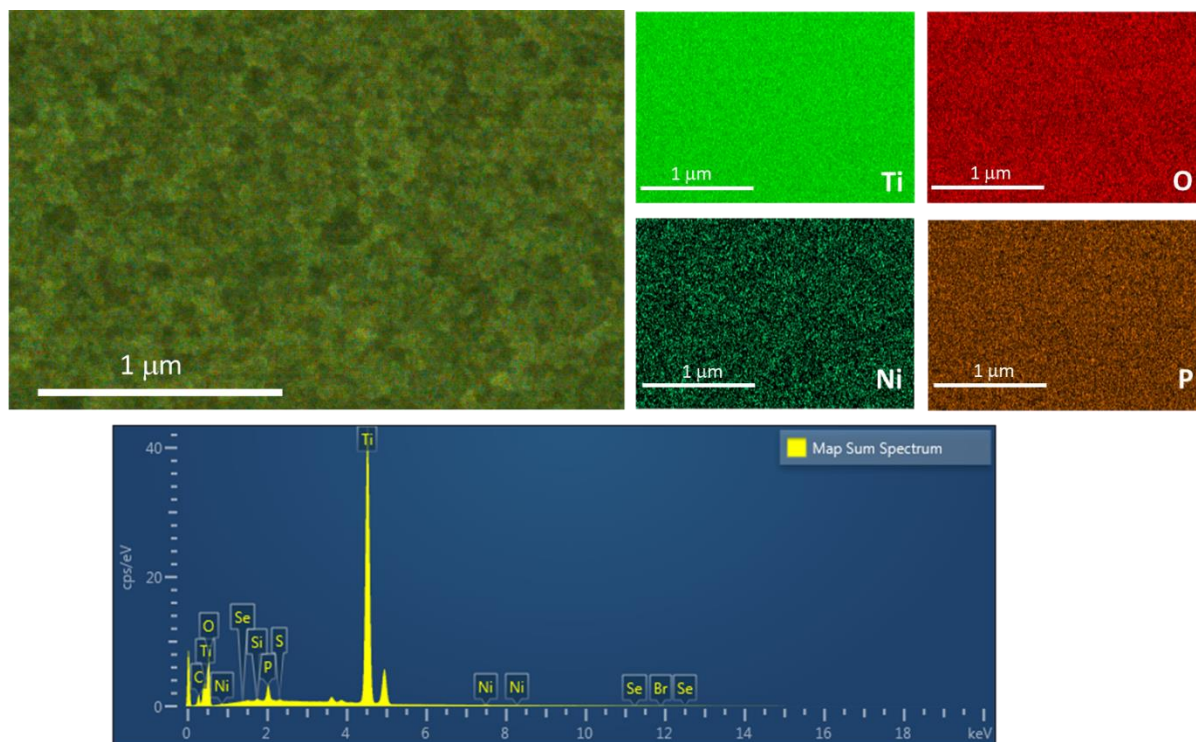


Figure S2.11 Top view EDX analysis of the NiP dispersion on the top of $\text{Sb}_2\text{Se}_3/\text{CdS}/\text{TiO}_2$ -meso, Ni is represented in green, and P is brown.

Figure S12. IPCE

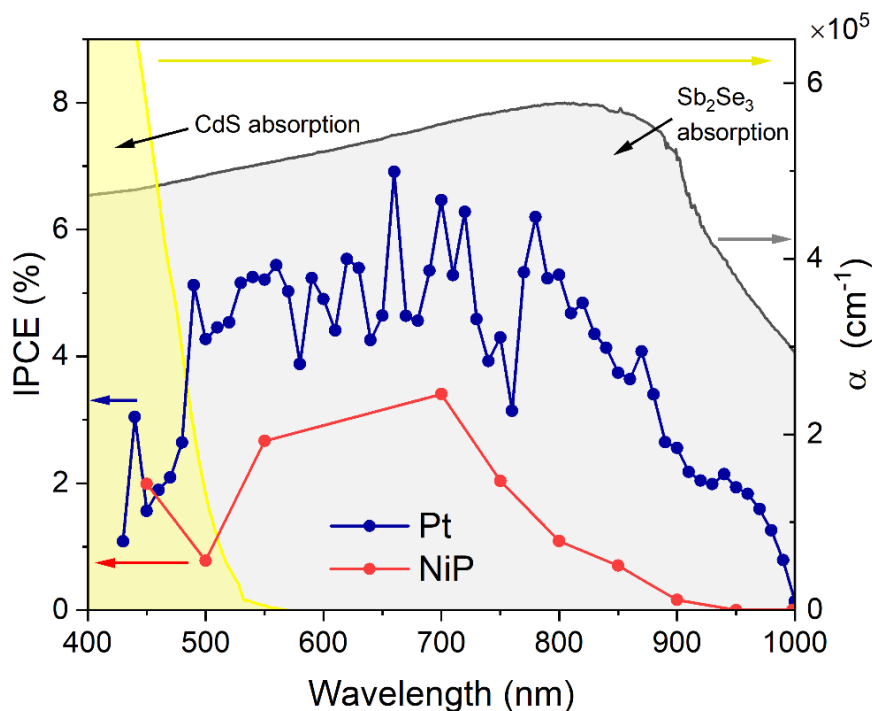


Figure S2.12. IPCE of $\text{Sb}_2\text{Se}_3/\text{CdS}/\text{TiO}_2\text{-meso}/\text{NiP}$ (red trace) and $\text{Sb}_2\text{Se}_3/\text{CdS}/\text{TiO}_2\text{-meso}/\text{Pt}$ (blue trace) at 0 V vs RHE in 0.1M Na_2SO_4 pH 3. Overlaid is the absorption spectra of the CdS and Sb_2Se_3 layers.

The IPCE responses show that the activity is significantly decreased at $\lambda < 500$ nm. This wavelength corresponds to the onset of light absorption by the CdS layer suggesting that photon absorption in this layer is not leading to useful photoelectron generation and that parasitic photon absorption occurs.

2.13 H_2 production over 5h CPP with the complete device

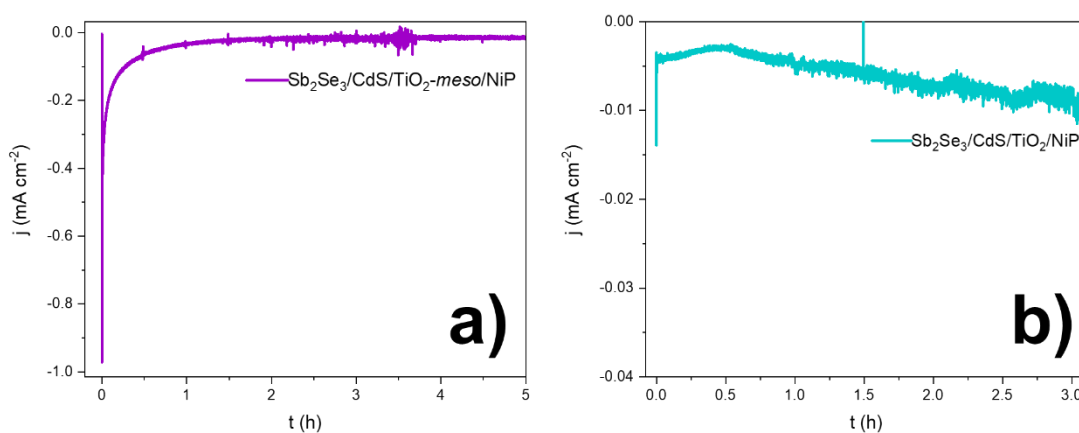


Figure S2.13 Controlled Potential Photoelectrolysis at 0 V vs RHE of $\text{Sb}_2\text{Se}_3/\text{CdS}/\text{TiO}_2\text{-meso}/\text{NiP}$ with (a) and without (b) the $\text{TiO}_2\text{-meso}$ layer in 0.1M Na_2SO_4 pH 3 at 100 mW cm^{-2} and $\lambda > 340\text{nm}$.

S14. Sb₂Se₃/CdS/TiO₂-*meso*/Pt

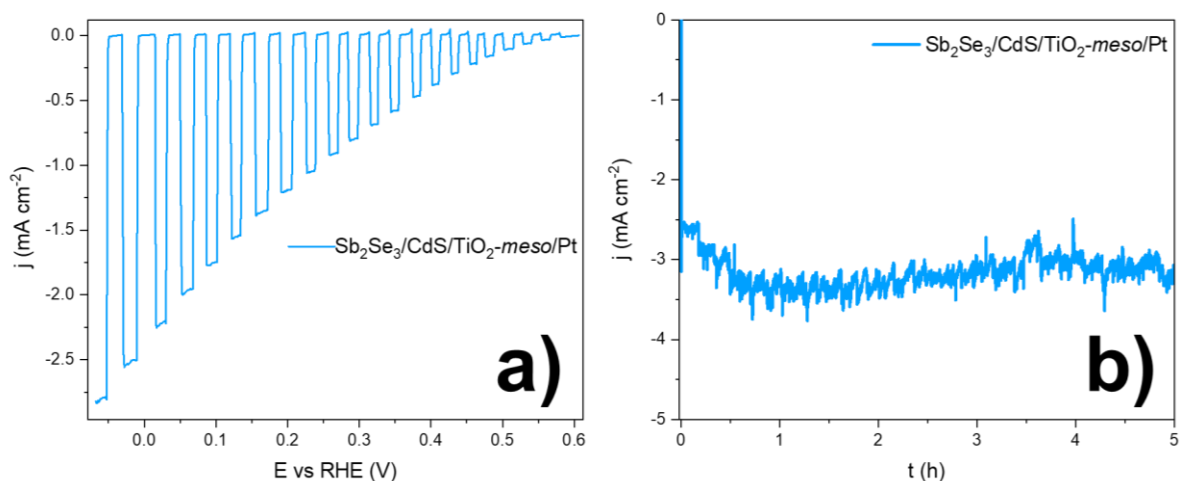


Figure S14: (a) Light chopped LSV of Sb₂Se₃/CdS/TiO₂-*meso*/Pt at 10mV s⁻¹, and (b) CPP at 0 V vs RHE in 0.1M Na₂SO₄ pH 3 at 100 mW cm⁻² and $\lambda > 340$ nm.

2.15 NiP reaction mechanism

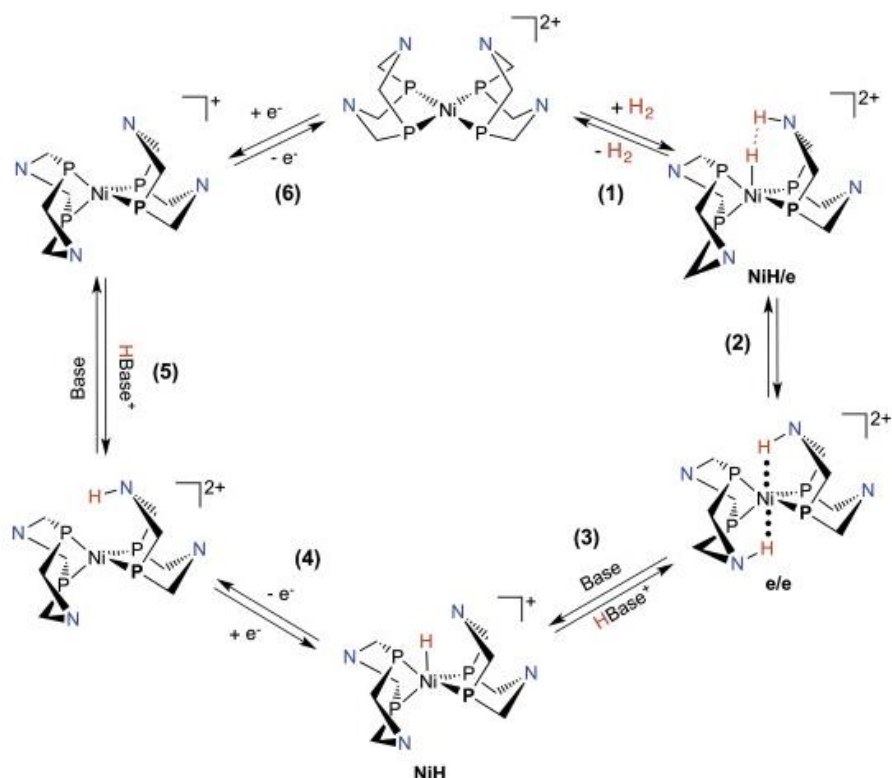


Figure S2.15. NiP reaction mechanism for H₂ production (anti-clockwise).¹⁵ Only the NiP core ([Ni(P₂^RN₂^{R'})₂]²⁺) is shown and the R and R' substituents are omitted for clarity. (P₂^RN₂^{R'} = bis(1,5-R'-diphospha-3,7-R''-diazacyclooctane).

2.16 LSV at 20% light intensity

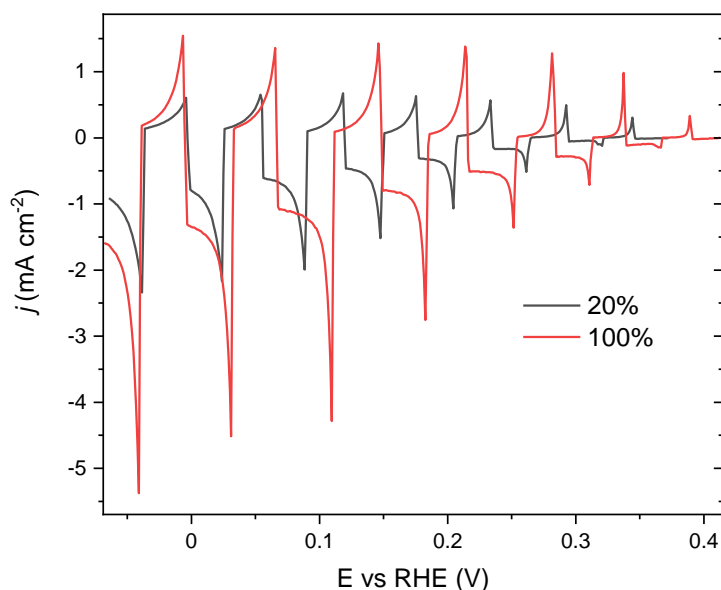


Figure S2.16: Chopped light LSV of Sb₂Se₃/CdS/TiO₂-meso/NiP at 10 mV s⁻¹ at 20 mW cm⁻² (20%, black) and 100 mW cm⁻² (100%, red) in 0.1 M Na₂SO₄ pH 3, and $\lambda > 340$ nm. Lowering the light intensity by using neutral density filters from 100 to 20 mW cm⁻² leads to a smaller percentage decrease in photocurrent (from 1.30 to 0.81 mA cm⁻² at 0 V vs RHE, ca. 38%) than the percentage change in light intensity (80% decrease) with FTO/Au/Sb₂Se₃/CdS/TiO₂/TiO₂-meso/NiP.

2.17 CPP at 20% light intensity

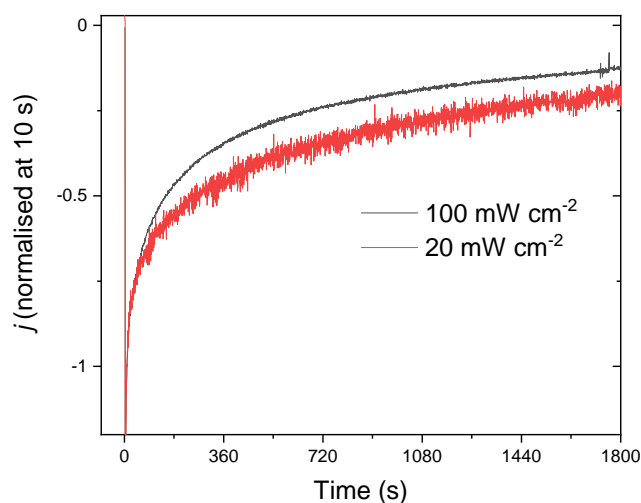


Figure S2.17. Normalised CPP at 0 V vs RHE of Sb₂Se₃/CdS/TiO₂-meso/NiP at 20 mW cm⁻² (red) and 100 mW cm⁻² (black) in 0.1M Na₂SO₄ pH 3. The lower light intensity also increases the stability with 20% of photocurrent being retained after 1800 s of operation when 20 mW cm⁻² is used compared to 11% at 100 mW cm⁻².

S18. SEM images after the bulk electrolysis

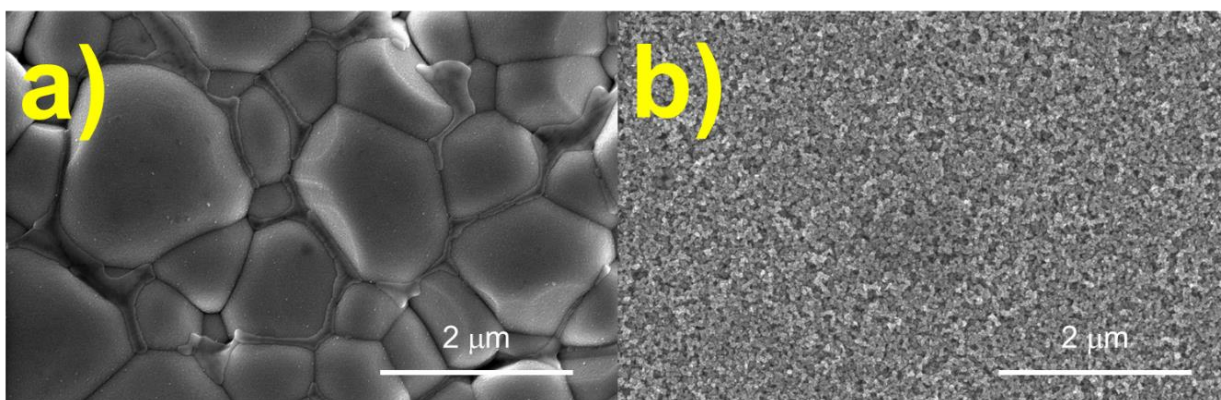


Figure S2.18 Top view SEM images of (a) $\text{Sb}_2\text{Se}_3/\text{CdS}/\text{TiO}_2/\text{NiP}$ and (b) $\text{Sb}_2\text{Se}_3/\text{CdS}/\text{TiO}_2\text{-meso}/\text{NiP}$ after 5 h of CPP at 0 V vs RHE in 0.1M Na_2SO_4 pH 3 at 100 mW cm^{-2} and $\lambda > 340 \text{ nm}$.

S2.19. XRD

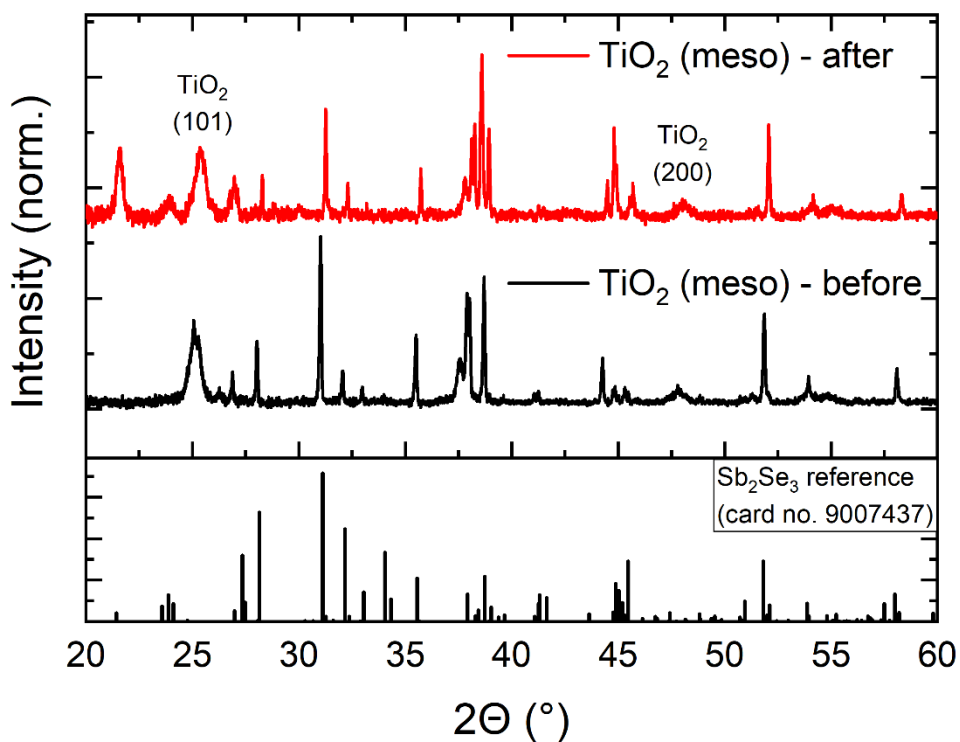


Figure S2.19 XRD pattern of $\text{Sb}_2\text{Se}_3/\text{CdS}/\text{TiO}_2\text{-meso}/\text{NiP}$ before (black trace) and after (red trace) the CPP test at 0 V vs RHE for 5 h.

2.20. Raman spectra after CPP at 0 V vs RHE in 0.1M Na₂SO₄ pH 3 for 5 h

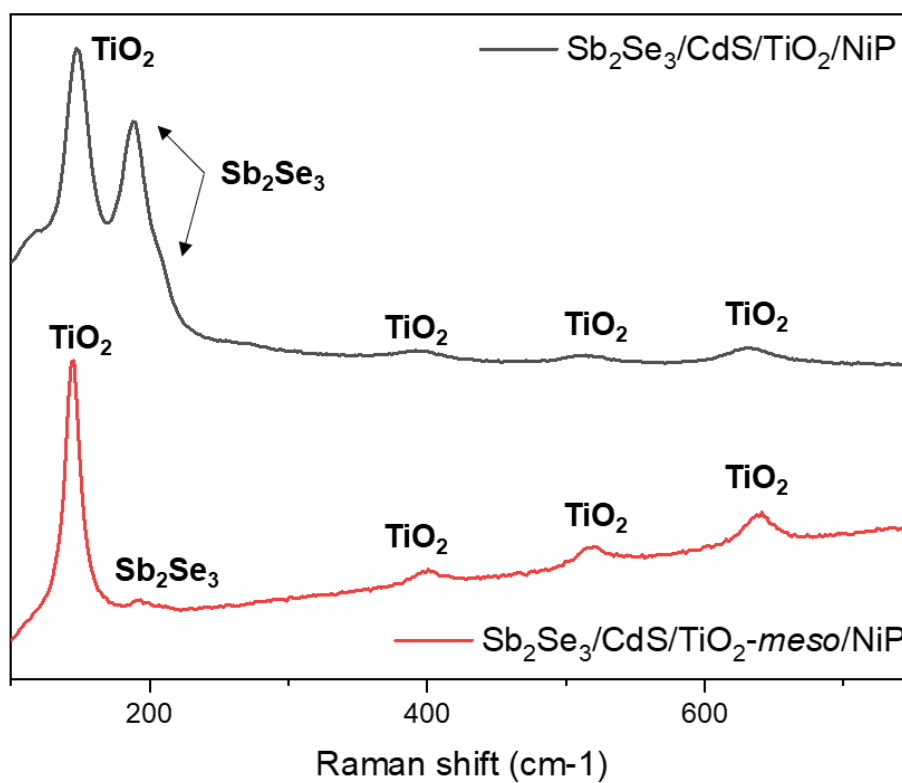


Figure S2.20. Raman spectra after 5 h of CPP at 0 V vs RHE on $\text{Sb}_2\text{Se}_3/\text{CdS}/\text{TiO}_2/\text{NiP}$ (black trace) and $\text{Sb}_2\text{Se}_3/\text{CdS}/\text{TiO}_2\text{-meso}/\text{NiP}$ (red trace) in 0.1M Na₂SO₄ pH 3 at 100 mW cm⁻² and $\lambda > 340$ nm.

S21. Light chopped LSV of $\text{Sb}_2\text{Se}_3/\text{CdS}/\text{TiO}_2\text{-meso}/\text{Pt}$ previously used with NiP as H_2 catalyst.

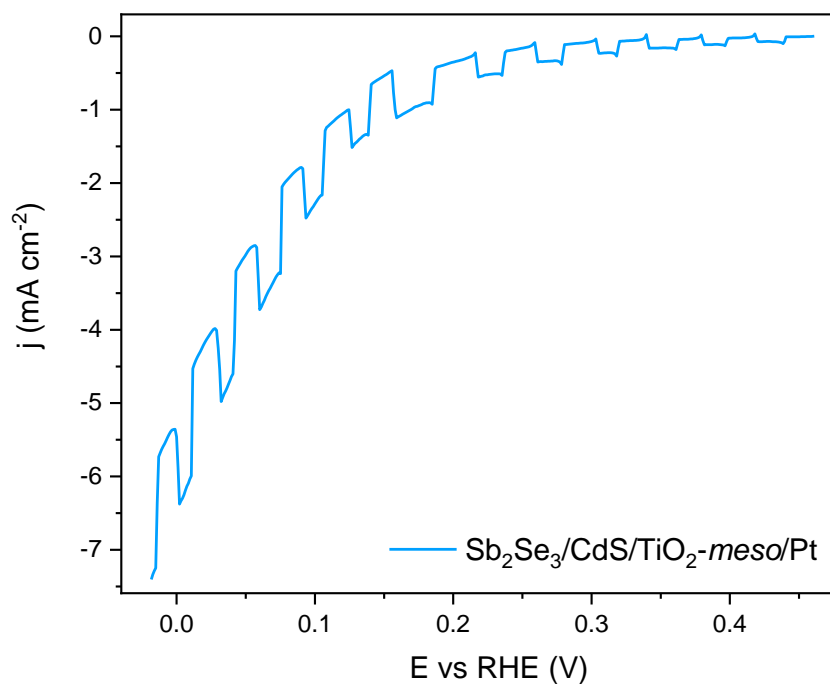


Figure S2.21. Light chopped LSV of $\text{Sb}_2\text{Se}_3/\text{CdS}/\text{TiO}_2\text{-meso}/\text{Pt}$ at 10 mV s^{-1} in $0.1 \text{ M Na}_2\text{SO}_4$ pH 3 at 100 mW cm^{-2} and $\lambda > 340 \text{ nm}$. For these experiments, **NiP** was used first as H_2 catalyst and went through light chopped LSV at 10 mV s^{-1} and the CPP test at 0 V vs RHE for 1 h in $0.1 \text{ M Na}_2\text{SO}_4$ pH 3 at 100 mW cm^{-2} and $\lambda > 340 \text{ nm}$, then **NiP** was stripped in 0.1 M NaOH from the electrode surface followed by the platinization of the sample.

Supporting tables

Table S1. NiP molecular catalyist loading.

Sample	NiP [nmol cm ⁻²]
TiO ₂ - <i>meso</i> (UV, 350°C N ₂)	37.36 ± 9.03
TiO ₂ - <i>meso</i> (450°C, air)	39.04 ± 8.36
Sb ₂ Se ₃ /CdS/TiO ₂ /NiP	7.08 ± 0.43
Sb ₂ Se ₃ /CdS/TiO ₂ - <i>meso</i> /NiP	45.76 ± 0.81

Table S2. XPS peak position of NiP catalyst pre and post CPP test for 5 h at 0 V vs RHE in 0.1M Na₂SO₄ pH 3 at 100 mW cm⁻² and λ > 340 nm.

Hybrid photoelectrode	CPP	N (1s)	P (2p)	Ni (2p 1/2)	Ni (2p 3/2)	Ref.
p-Si/TiO ₂ /NiP	pre	399.6	132.5	872	854.8	4
	post	400.2	132		854.8	
FTO/TiO ₂ /NiP	pre	396.4	129.4	868.9	851.5	8
	post	396.2	129	869.1	851.5	
Au/La ₅ Ti ₂ Cu _{0.9} Ag _{0.1} S ₅ O ₇ /TiO ₂ /NiP	pre	398.67	132.5	860.4	855	5
	post	400.2	132.5	na	na	
Sb ₂ Se ₃ /CdS/TiO ₂ - <i>meso</i> /NiP	pre	399.6	132.6	872.1	854.6	This work
	post	399.8	134.3	na	na	
	NiP	399.5	133.1	872	854.8	

Table S3. Hybrid photocathodes for H₂ production.

Photocathode	j (mA cm ⁻²) @ 0 V vs RHE	Stability (%) t (h)	Electrolyte	Light source	Ref.
p-Si/TiO ₂ /NiP	0.35	28% 24	0.1 M Acetic Acid pH 4.5	AM 1.5G, 100 mW cm ⁻² λ > 400 nm	4
Au/LTCA/TiO ₂ /NiP LTCA: La ₅ Ti ₂ Cu _{0.9} Ag _{0.1} S ₅ O ₇	0.5	8% 6	0.1 M Na ₂ SO ₄ pH 3	AM 1.5G, 100 mW cm ⁻²	5
*FTO/TiO ₂ /NiP	0.2	25% 8	0.1 M Na ₂ SO ₄ pH 3	*	8
Sb ₂ Se ₃ /CdS/TiO ₂ - <i>meso</i> /NiP	1.3	3% 1	0.1 M Na ₂ SO ₄ pH 3	100 mW cm ⁻² λ > 340 nm	This work
Sb ₂ Se ₃ /CdS/TiO ₂ - <i>meso</i> /NiP	0.8	20% 0.5	0.1 M Na ₂ SO ₄ pH 3	20 mW cm ⁻² λ > 340 nm	This work
p-Si/ALD-TiO ₂ /SC-TiO ₂ /Co _{C11P} /ALD-TiO ₂	1.3	77% 1	1 M PBS pH 7	AM 1.5G, 100 mW.cm ⁻²	16

p-Si/TiO ₂ (ALD/DB)/Ni(N ₅) ^{HA}	1	100%	0.1 M PBS pH 7	AM 1.5G, 100 mW cm ⁻²	17
p-Si/TiO ₂ (ALD/DB)/Co(N ₅) ^{HA}	0.7	100%	0.1 M PBS pH 7	AM 1.5G, 100 mW cm ⁻²	17
p-Si/TiO ₂ (ALD/DB)/CoPy ^{HA}	0.4	84% 6	0.1 M PBS pH 7	AM 1.5G, 100 mW cm ⁻²	17
Si/TiO ₂ /Co(CR-DCP)	0.68	100% 10	0.1 M ABS pH 4.5	AM 1.5G, 100 mW cm ⁻² $\lambda > 400$ nm	18
CuFe _x O _y /TiO ₂ /CoHEC	4.5 0.4 V vs RHE	67% 20 min	0.2 M PBS pH 6.7	1 sun visible light (400–780 nm)	19
p-Si/TiO ₂ /CoPy-4- CONH(OH)	0.319	≈100% 2	0.1 M BBS pH 9	AM 1.5G, 100 mW cm ⁻² $\lambda > 400$ nm	20
p-Si/TiO ₂ /CoPy-4-PO ₃ H ₂	0.18	75% 2	0.1 M BBS pH 9	AM 1.5G, 100 mW cm ⁻² $\lambda > 400$ nm	20
p-Si/TiO ₂ /CoPy-4-COOH	0.158	66% 2	0.1 M BBS pH 9	AM 1.5G, 100 mW cm ⁻² $\lambda > 400$ nm	20
GaInP ₂ /TiO ₂ / (OOCpy)Co(dmGH) ₂ (Cl)/Ti O ₂	9	56% 20	0.1M NaOH pH 13	1-sun illumination 100 mW cm ⁻²	21

*This study did not use a light absorber, instead a potential of -0.25 V vs RHE was applied. SC- Spin coating, ALD-Atomic Layer Deposition, DB-Doctor-blading, ABS: Acetic buffer solution, PBS: Phosphate buffer solution, BBS: Borate buffer solution

Table S3 compares the PEC performance of hybrid photocathodes using NiP molecular catalyst. The stability was defined as the photocurrent measured at the beginning of the CPP ($J_0 @ t = 0$) against the photocurrent measured at certain time ($J @ t (h)$) at 0 V vs RHE, according to (2).

$$\% \text{ Stability} = \frac{J @ t (h)}{J_0 @ t=0} \quad (2)$$

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